ACNV2601

High Insulation Voltage 10-MBd Digital Optocoupler

Data Sheet



Description

The ACNV2601 is an optically coupled gate that combines an AlGaAs light-emitting diode and an integrated photo detector housed in a widebody package. The distance-through-insulation (DTI) between the emitting diode and photo-detector is at 2 mm. The output of the detector IC is an open collector Schottky clamped transistor. The internal shield provides a guaranteed common mode transient immunity specification of 20 kV/µs at $V_{cm} = 1500V$.

With creepage and clearance of greater than 13 mm, ACNV2601 is designed to provide high isolation voltage (7500 V_{rms}). It can withstand a continuous high working voltage of 2262 V_{peak} and a surge voltage of 12,000 V_{peak}, meeting IEC60747-5-5, UL, and CSA standard for reinforced insulation. ACNV2601 provides the high insulation voltage protection at a high data rate of 10 MBd.

CAUTION It is advised that normal static precautions be taken in handling and assembly of this component to prevent damage and/or degradation which may be induced by ESD. The components featured in this data sheet are not to be used in military or aerospace applications or environments

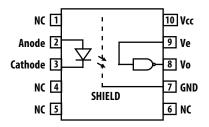
Features

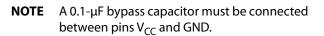
- High voltage insulation with minimum 13-mm creepage and clearance
- 20 kV/µs minimum common mode rejection (CMR) at V_{CM} = 1500V
- High speed: 10 MBd typical
- TTL compatible
- Open collector output
- Guaranteed AC and DC performance over wide temperature: -40°C to +105°C
- Available in 10-pin widebody packages
- Safety approval:
 - Approval at 7500 V_{rms} for 1 minute per UL1577
 - CSA
 - IEC/EN/DIN EN 60747-5-5 with $V_{iorm} = 2262 V_{peak}$

Applications

- High voltage insulation
- Instrument input/output isolation
- Line receivers
- Ground loop elimination
- Isolation of high-speed logic systems
- Microprocessor system interfaces

Functional Diagram





Ordering Information

ACNV2601 is UL recognized with 7500 V_{rms} for 1 minute per UL1577.

Part Number	Option	Package	Surface	Gull Wing	Tape &	UL 7500 V _{rms} /	IEC/EN/DIN EN	Quantity
i arcitanisci	RoHS Compliant	ruckuge	Mount	cunting	Reel	1 Minute Rating	60747-5-5	Quantity
ACNV2601	-000E	500 mil				Х	Х	35 per tube
	-300E	DIP-10	Х	Х		Х	Х	35 per tube
	-500E		Х	Х	Х	Х	Х	500 per reel

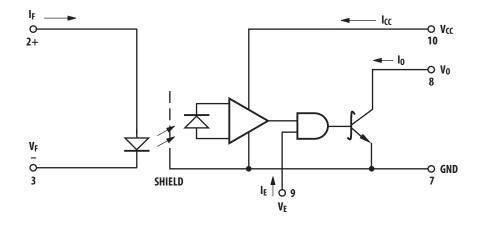
To order, choose a part number from the Part Number column and combine with the desired option from the Option column to form an order entry.

Example 1:

ACNV2601-500E to order product of 500 mil DIP-10 Widebody with Gull Wing Surface Mount package in Tape and Reel packaging with both UL 7500 V_{rms}/1 min and IEC/EN/DIN EN 60747-5-5 Safety Approval in RoHS compliant.

Option data sheets are available. Contact your Broadcom sales representative or authorized distributor for information.

Schematic



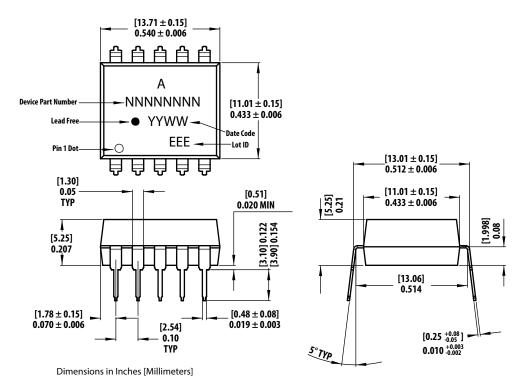


LED	ENABLE	OUTPUT
On	Н	L
Off	Н	Н
On	L	Н
Off	L	Н
On	NC	L
Off	NC	Н

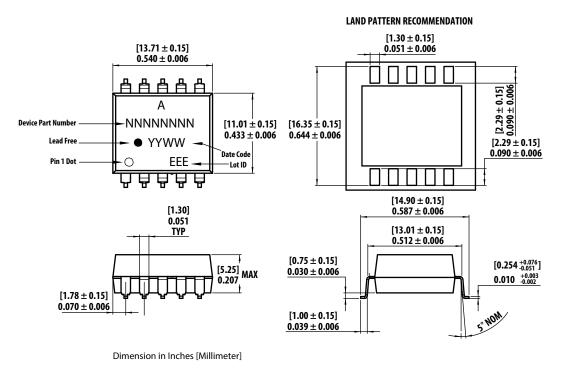
Truth Table (Positive Logic)

Package Drawings

10-Pin Widebody (500 mils) DIP Package



10-Pin Widebody (500 mils) DIP Package with Gull Wing Surface Mount Option 300



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Solder Reflow Profile

Recommended reflow condition as per JEDEC Standard, J-STD-020 (latest revision). Non-Halide Flux should be used.

Insulation and Safety Related Specifications

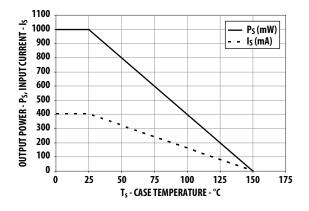
Parameter	Symbol	ACNV2601	Unit	Conditions
Minimum External Air Gap (External Clearance)	L(101)	13	mm	Measured from input terminals to output terminals, shortest distance through air.
Minimum External Tracking (External Creepage)	L(102)	13	mm	Measured from input terminals to output terminals, shortest distance path along body.
Minimum Internal Plastic Gap (Internal Clearance)		2.0	mm	Through insulation distance conductor to conductor, usually the straight line distance thickness between the emitter and detector.
Minimum Internal Tracking (Internal Creepage)		4.6	mm	Measured from input terminals to output terminals, along internal cavity.
Tracking Resistance (Comparative Tracking Index)	СТІ	200	V	DIN IEC 112/VDE 0303 Part 1.
Isolation Group		Illa		Material Group (DIN VDE 0110, 1/89, Table 1).

IEC/EN/DIN EN 60747-5-5 Insulation Characteristics^a

Description	Symbol	Characteristic	Unit
Installation Classification per DIN VDE 0110/1.89, Table 1			
For Rated Mains Voltage \leq 600 V _{rms}		I – IV	
For Rated Mains Voltage \leq 1000 V _{rms}		I – III	
Climatic Classification		55/105/21	
Pollution Degree (DIN VDE 0110/1.89)		2	
Maximum Working Insulation Voltage	V _{IORM}	2262	V _{peak}
Input to Output Test Voltage, Method b ^a	V _{PR}	4241	V _{peak}
V_{IORM} x 1.875 = V_{PR} , 100% Production Test with t_m = 1 sec, Partial Discharge < 5 pC			
Input to Output Test Voltage, Method a ^a	V _{PR}	3619	V _{peak}
V_{IORM} x 1.6 = V_{PR} , Type and Sample Test, t _m = 10 sec, Partial Discharge < 5 pC			
Highest Allowable Overvoltage (Transient Overvoltage t _{ini} = 60 sec)	V _{IOTM}	12000	V _{peak}
Safety-Limiting Values — Maximum Values Allowed in the Event of a Failure			
Case Temperature	Ts	150	°C
Input Current ^b	I _{S, INPUT}	400	mA
Output Power ^b	P _{S, OUTPUT}	1	W
Insulation Resistance at T_s , $V_{IO} = 500V$	R _S	>10 ⁹	Ω

a. Refer to the optocoupler section of the Isolation and Control Components Designer's Catalog, under Product Safety Regulations section, (IEC/EN/DIN EN 60747-5-5) for a detailed description of Method a and Method b partial discharge test profiles.

b. Refer to the following figure for dependence of P_S and I_S on ambient temperature:



NOTE These optocouplers are suitable for safe electrical isolation only within the safety limit data. Maintenance of the safety data shall be ensured by means of protective circuits.

Absolute Maximum Ratings

Parameter	Symbol	Min.	Max.	Unit
Storage Temperature	T _S	-55	125	°C
Operating Temperature	T _A	-40	105	°C
Average Input Current	I _{F(AVG)}		20	mA
Reverse Input Voltage	V _R	_	3	V
Input Power Dissipation	PI	_	40	mW
Supply Voltage (1 Minute Maximum)	V _{CC}	_	7	V
Enable Input Voltage (Not to exceed V _{CC} by more than 500 mV)	V _E	_	V _{CC} + 0.5	V
Enable Input Current	١ _E	—	5	mA
Output Collector Current	Ι _Ο	_	50	mA
Output Collector Voltage	V _O	_	7	V
Output Collector Power Dissipation	Po	—	85	mW
Lead Solder Temperature	T _{LS}		245°C for 10 sec, up to seat plane	

Recommended Operating Conditions

Parameter	Symbol	Min.	Max.	Unit	Notes
Input Current, Low Level	I_{FL}^{a}	0	250	μΑ	
Input Current, High Level	I _{FH} b	9	16	mA	с
Power Supply Voltage	V _{CC}	4.5	5.5	V	
Low Level Enable Voltage	V _{EL}	0	0.8	V	
High Level Enable Voltage	V _{EH}	2.0	V _{CC}	V	
Operating Temperature	T _A	-40	105	°C	
Fan Out (at $R_L = 1 \ k\Omega$)	Ν	_	5	TTL Loads	
Output Pull-up Resistor	R _L	330	4k	Ω	

a. The off condition can also be guaranteed by ensuring that V_{FL} 0.8V.

b. The initial switching threshold is 8 mA or less. It is recommended that 9 mA to 16 mA be used for best performance and to permit at least a 20% LED degradation guardband.

c. Peaking circuits may produce transient input currents up to 50-mA, 50-ns maximum pulse width, provided average current does not exceed 20 mA.

Electrical Specifications (DC)

Over recommended operating conditions unless otherwise specified. All typicals at $V_{CC} = 5V$, $T_A = 25^{\circ}C$.

Parameter	Symbol	Min.	Тур.	Max.	Unit	Test Conditions	Fig.	Notes
High Level Output Current	I _{OH}	—	5.5	100	μA	$V_{CC} = 5.5V, V_E = 2.0V$		а
						$V_{O} = 5.5V$, $I_{FL} = 250 \ \mu A$		
Input Threshold Current	I _{TH}	_	3.5	8	mA	$V_{CC} = 5.5V, V_E = 2.0V,$ $V_O = 0.6V, I_{OL} > 13 \text{ mA}$	1, 2	a
Low Level Output Voltage	V _{OL}		0.35	0.6	V	$V_{CC} = 5.5V, V_E = 2.0V,$ $I_F = 8 \text{ mA}, I_{OL(Sinking)} = 13 \text{ mA}$	1, 2, 3, 4	а
High Level Supply Current	I _{CCH}	—	7.0	12	mA	$V_{\rm E} = 0.5 V$ $V_{\rm CC} = 5.5 V$,		
		_	6.5	—	-	$V_{\rm E} = V_{\rm CC}$ $I_{\rm F} = 0 \rm mA$		
Low Level Supply Current	I _{CCL}	—	9.0	13	mA	$V_{\rm E} = 0.5V$ $V_{\rm CC} = 5.5V$,		
		—	8.5			$V_{\rm E} = V_{\rm CC}$ $I_{\rm F} = 10 \rm mA$		
High Level Enable Current	I _{EH}	—	-0.7	—	mA	$V_{CC} = 5.5V, V_E = 2.0V$		
Low Level Enable Current	I _{EL}	—	-0.9		mA	$V_{CC} = 5.5 V, V_E = 0.5 V$		
High Level Enable Voltage	V _{EH}	2.0	—		mA	$V_{CC} = 5.5 \text{ V}, V_{E} = 2.0 \text{ V}$		а
Low Level Enable Voltage	V _{EL}			0.8	mA	$V_{CC} = 5.5 V, V_E = 0.5 V$		
Input Forward Voltage	V _F	1.25	1.64	1.85	V	$T_A = 25^{\circ}C$ $I_F = 10 \text{ mA}$	5	
		1.2		2.05	-			
Input Reverse Breakdown Voltage	BV _R	5	-		V	$I_{R} = 100 \ \mu\text{A}, T_{A} = 25^{\circ}\text{C}$		
Input Capacitance	C _{IN}	—	60		pF	$f = 1 MHz, V_F = 0V$		
Input Diode Temperature Coefficient	$\Delta V_F / \Delta T_A$		-1.9	-	mV/°C	I _F = 10 mA		

a. No external pull-up is required for a high logic state on the enable input. If the V_E pin is not used, tying V_E to V_{CC} results in improved CM_R performance

Switching Specifications (AC)

Over recommended temperature ($T_A = -40^{\circ}C$ to $+105^{\circ}C$), $V_{CC} = 5V$, $I_F = 10$ mA unless otherwise specified. All typicals are at $T_A = 25^{\circ}C$, $V_{CC} = 5V$.

Parameter	Symbol	Min.	/lin. Typ.	Max.	Unit	Test Conditions	Fig.	Notes
Propagation Delay Time to High Output Level	t _{PLH}	30	50	80	ns	$T_A = 25^{\circ}C$ $R_L = 350\Omega$,	6, 7, 8	a, b
				120		C _L = 15 pF		
Propagation Delay Time to Low	t _{PHL}	35	55	80	ns	$T_A = 25^{\circ}C$		c, b
Output Level				120				
Pulse Width Distortion	t _{PHL} – t _{PLH}	—	5	40	ns	$R_L = 350\Omega, C_L = 15 \text{ pF}$	6, 7, 8, 9	b
Propagation Delay Skew	t _{psk}	_		50	ns	_		d, b
Output Rise Time (10% to 90%)	T _r	—	25		ns	_	10	b
Output Fall Time (10% to 90%)	T _f	—	10		ns	_	10	b
Propagation Delay Time of Enable from V _{EH} to V _{EL}	t _{ELH}	—	30	-	ns	$\begin{aligned} R_L &= 350\Omega, \ C_L &= 15 \ pF, \\ V_{EL} &= 0V, \ V_{EH} &= 3V \end{aligned}$	11, 12	e
Propagation Delay Time of Enable from V _{EL} to V _{EH}	t _{EHL}	—	20	_	ns	$R_L = 350\Omega, C_L = 15 \text{ pF},$ $V_{EL} = 0V, V_{EH} = 3V$	11, 12	f
Output High Level Common Mode Transient Immunity	CM _H	20	25	_	kV/μs	$\begin{split} V_{CC} &= 5 \text{ V}, \text{ I}_{\text{F}} = 0 \text{ mA}, \\ V_{O(\text{MIN})} &= 2 \text{ V}, \text{ R}_{\text{L}} = 350 \Omega, \\ T_{\text{A}} &= 25^{\circ}\text{C}, \text{ V}_{\text{CM}} = 1500 \text{ V} \end{split}$	13	g, h, b
Output Low Level Common Mode Transient Immunity	CM _L	20	25	_	kV/μs	$\begin{split} V_{CC} &= 5V, I_F = 10 \text{ mA}, \\ V_{O(MAX)} &= 0.8V, R_L = 350\Omega, \\ T_A &= 25^\circ\text{C}, V_{CM} = 1500V \end{split}$		h, i, b

a. The t_{PLH} propagation delay is measured from the 5 mA point on the falling edge of the input pulse to the 1.5V point on the rising edge of the output pulse.

b. No external pull-up is required for a high logic state on the enable input. If the V_E pin is not used, tying V_E to V_{CC} results in improved CM_R performance.

c. The tPHL propagation delay is measured from the 5 mA point on the rising edge of the input pulse to the 1.5V point on the falling edge of the output pulse.

d. t_{PSK} is equal to the worst-case difference in t_{PHL} and/or t_{PLH} that is seen between units at any given temperature and specified test conditions.

e. The t_{ELH} enable propagation delay is measured from the 1.5V point on the falling edge of the enable input pulse to the 1.5V point on the rising edge of the output pulse.

f. The t_{EHL} enable propagation delay is measured from the 1.5V point on the rising edge of the enable input pulse to the 1.5V point on the falling edge of the output pulse.

g. CM_H is the maximum tolerable rate of rise of the common mode voltage to ensure that the output remains in a high logic state (i.e., $V_O > 2.0V$).

h. For sinusoidal voltages, $(|dV_{CM}|/dt)_{max} = \pi f_{CM}V_{CM(p-p)}$.

i. CM_L is the maximum tolerable rate of fall of the common mode voltage to ensure that the output remains in a low logic state (i.e., $V_O < 0.8V$).

Package Characteristics

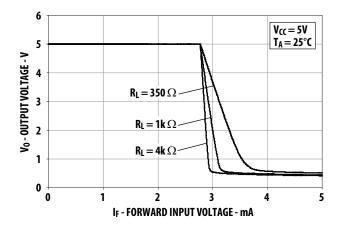
All typicals are at $T_A = 25^{\circ}C$.

Parameter	Symbol	Min.	Тур.	Max.	Unit	Test Conditions	Fig.	Notes
Input-Output Insulation	V _{ISO}	7500	—	—	V _{rms}	RH < 50% for 1 min., T _A = 25°C		a, b
Input-Output Resistance	R _{I-O}	10 ¹²	—	—	Ω	$V_{I-O} = 500V$		а
Input-Output Capacitance	C _{I-O}	—	0.5	0.6	pF	f = 1 MHz, T _A = 25°C		а

a. Device considered a two-terminal device: pins 1, 2, 3, 4 and 5 shorted together, and pins 6, 7, 8, 9 and 10 shorted together.

b. In accordance with UL1577, each optocoupler is proof tested by applying an insulation test voltage \geq 9000 V_{rms} for one second (leakage detection current limit, I_{LO} \leq 5 µA). This test is performed before the 100% production test for partial discharge (Method b) shown in the IEC/EN/DIN EN 60747-5-5 Insulation Characteristics^a table, if applicable.

Figure 1 Typical Output Voltage vs. Forward Input Voltage Current



6 ITH - INPUT THRESHOLD CURRENT - mA 5 4 $\mathbf{R}_{\mathbf{L}} = \mathbf{350}\,\Omega, \mathbf{1k}\,\Omega, \mathbf{4k}\,\Omega$ 3 2 1 $V_{CC} = 5.0 V$ $V_{\rm E} = 0.6 \, \rm V$ 0 -60 -40 -20 20 40 60 80 100 120 0

Figure 2 Typical Input Threshold Current vs. Temperature

Figure 3 Typical Low Level Output Voltage vs. Temperature

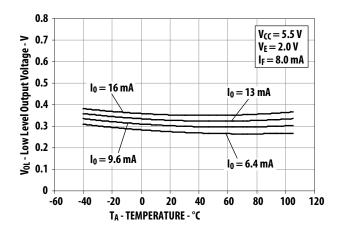


Figure 5 Typical Input Diode Forward Characteristic

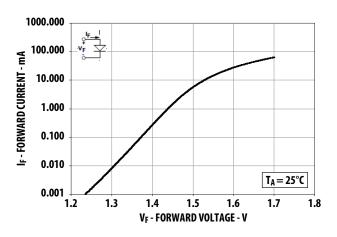


Figure 4 Typical Low Level Output Current vs. Temperature

TA - TEMPERATURE - °C

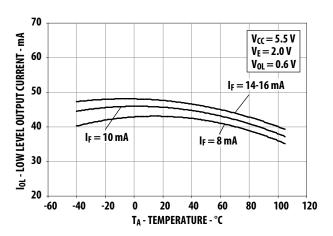
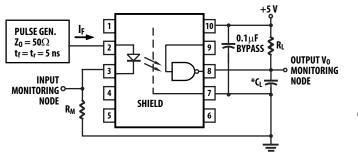




Figure 6 Test Circuit for t_{PHL} and t_{PLH}



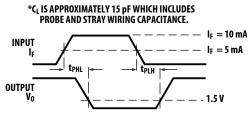


Figure 7 Typical Propagation Delay vs. Temperature

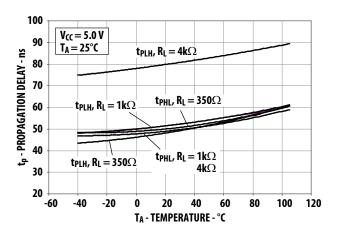


Figure 9 Typical Pulse Width Distortion vs. Temperature

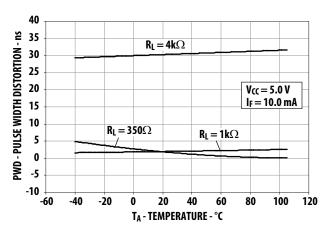
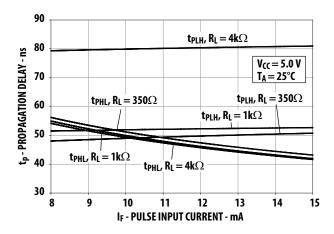


Figure 8 Typical Propagation Delay vs. Pulse Input Current





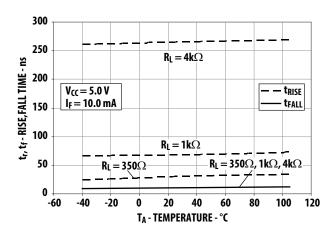
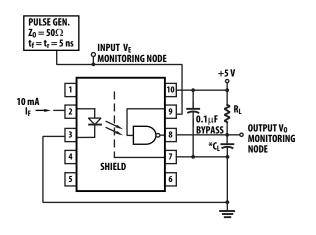
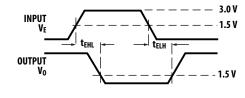


Figure 11 Test Circuit for t_{EHL} and t_{ELH}





*CL IS APPROXIMATELY 15 pF WHICH INCLUDES PROBE AND STRAY WIRING CAPACITANCE.

Figure 12 Typical Enable Propagation Delay vs. Temperature

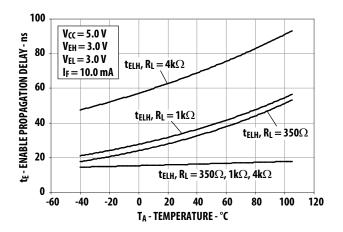


Figure 13 Test Circuit for Common Mode Transient Immunity and Typical Waveforms

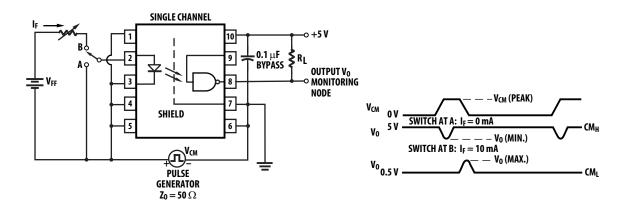
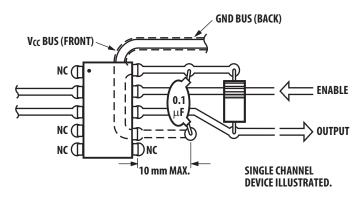


Figure 14 Recommended Printed Circuit Board Layout



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